

IUCr2017, Hyderabad, IN  
25-08-2017



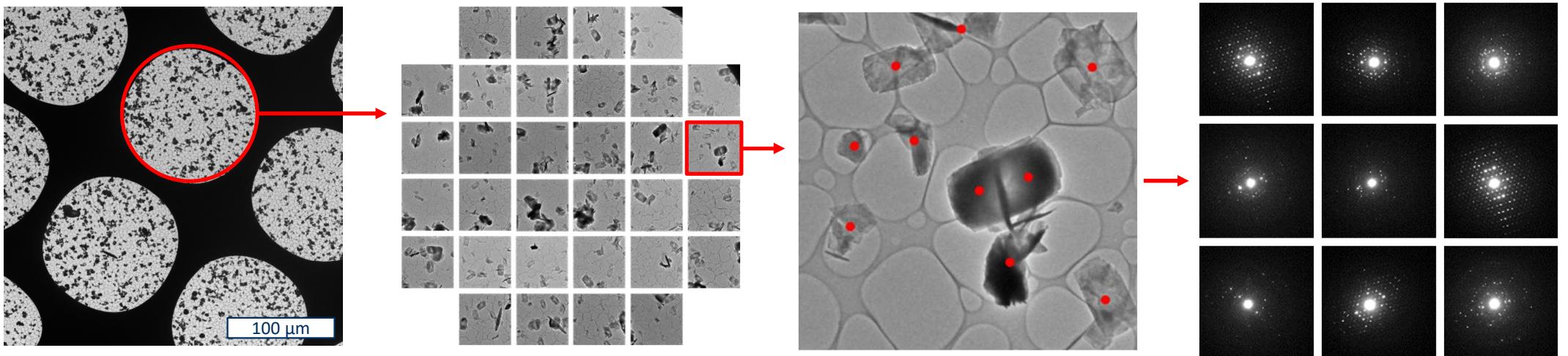
# Serial Electron Crystallography

Structure determination & phase analysis

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Stockholm University

# Serial electron crystallography



Randomly oriented crystals

1 crystal = 1 diffraction pattern

Combine data from many crystals

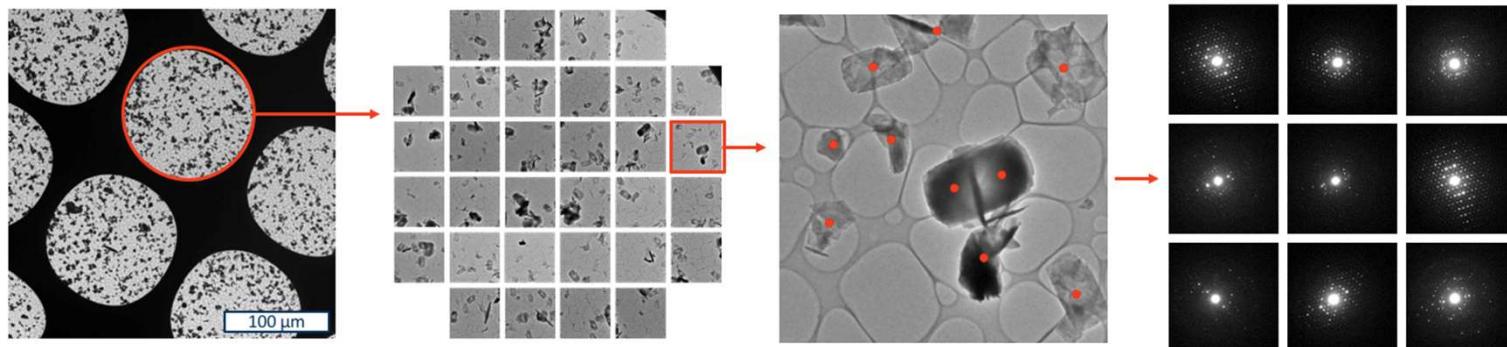
# Serial electron crystallography

## *Why use a TEM?*

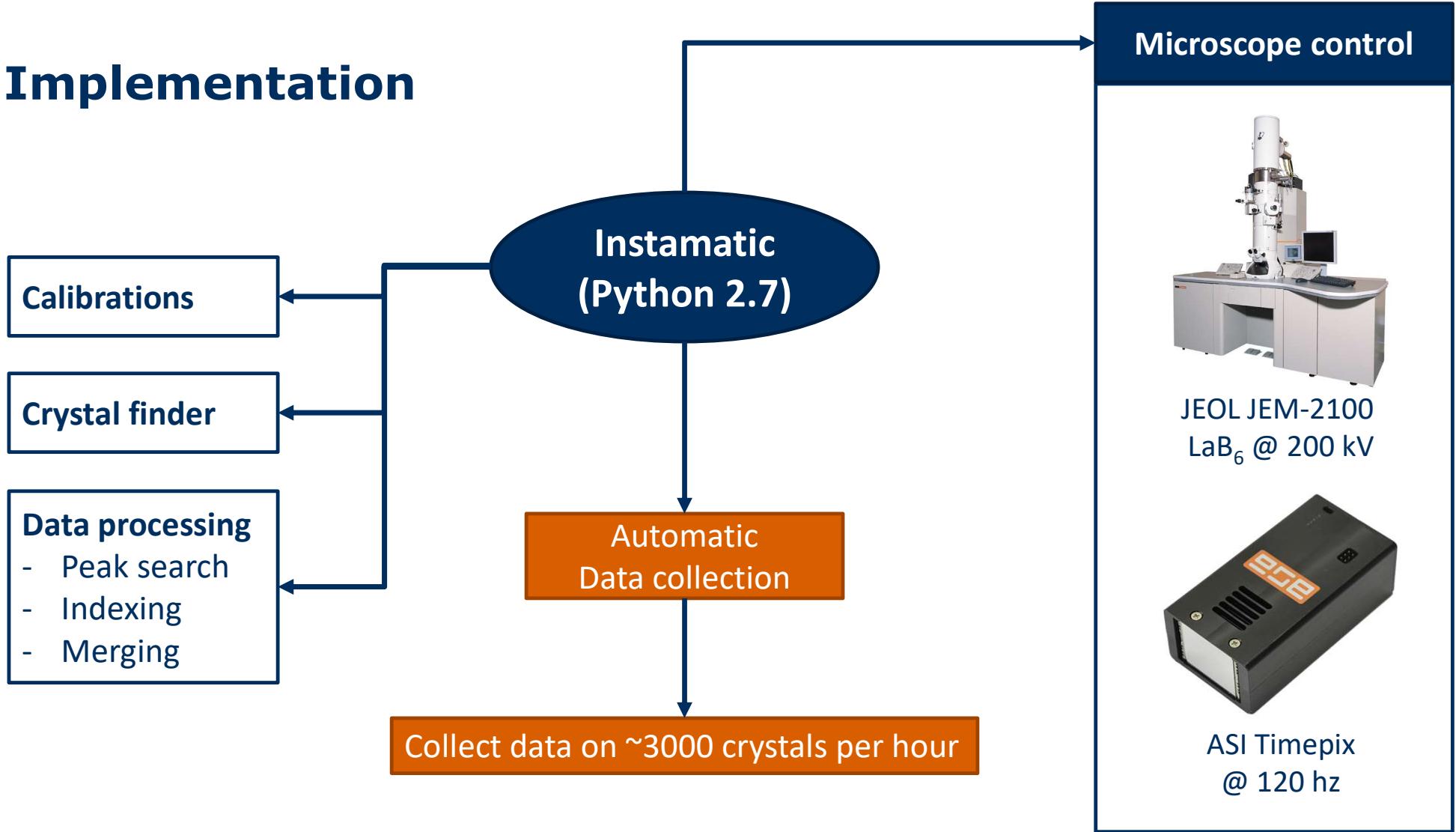
- Electron beam is very intense
- Crystals can be located from images
- TEMs can be programmed
- There is one in many labs

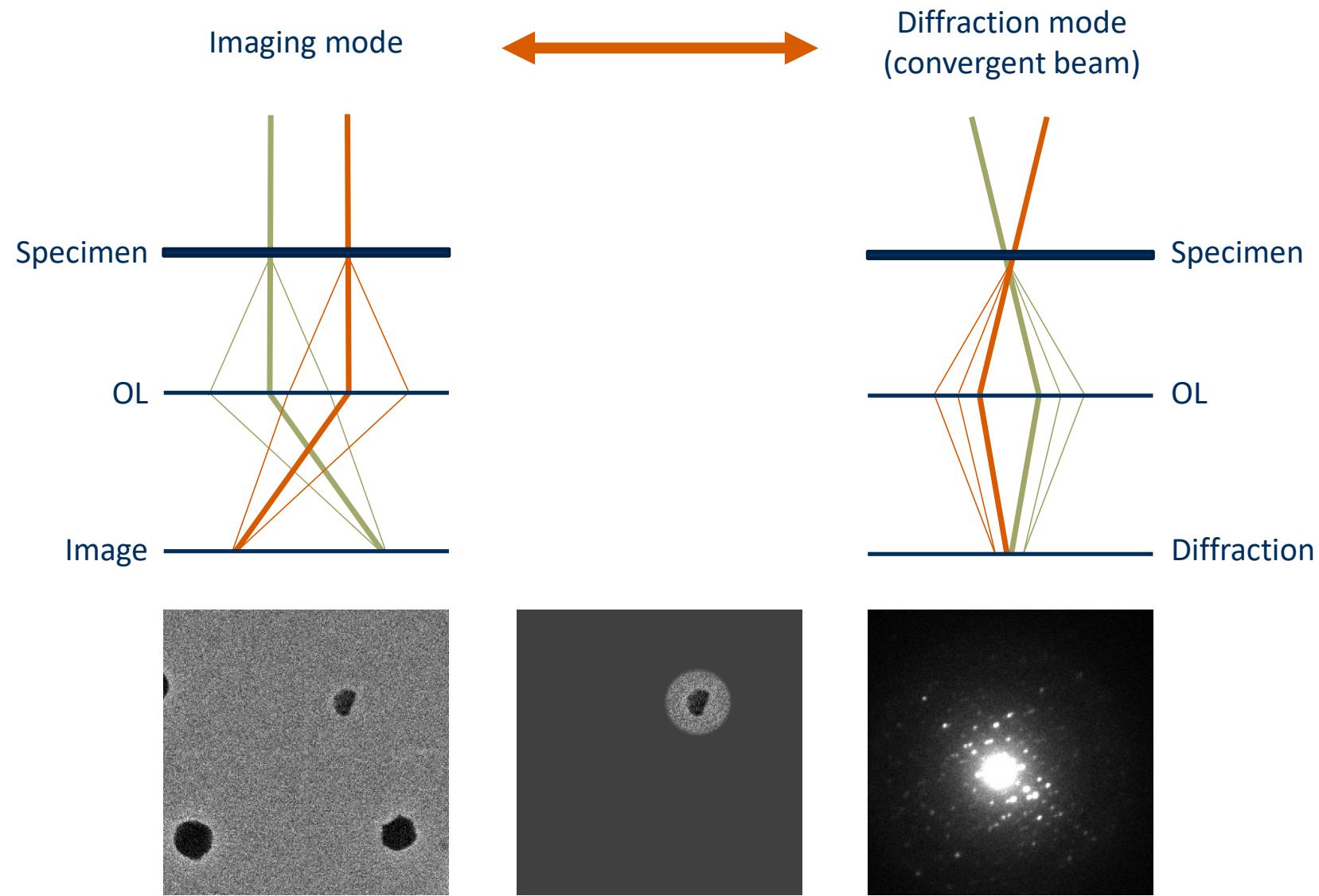
## *Advantages*

- Beam damage is avoided
- Simple alignment
- No rotation needed
- Fully automatic data collection



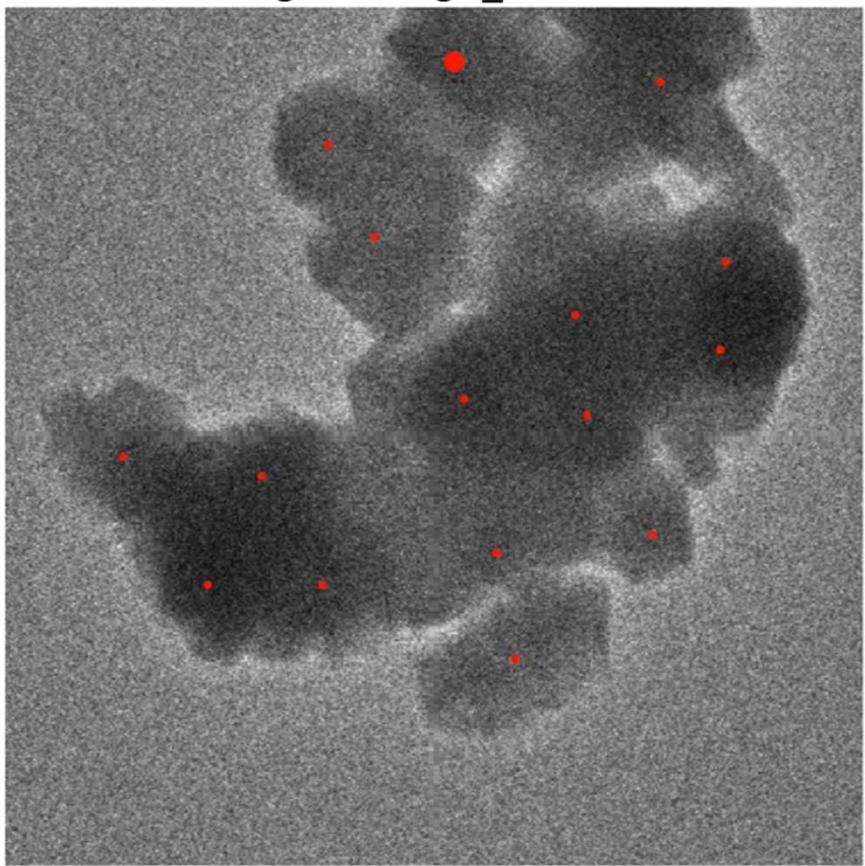
# Implementation



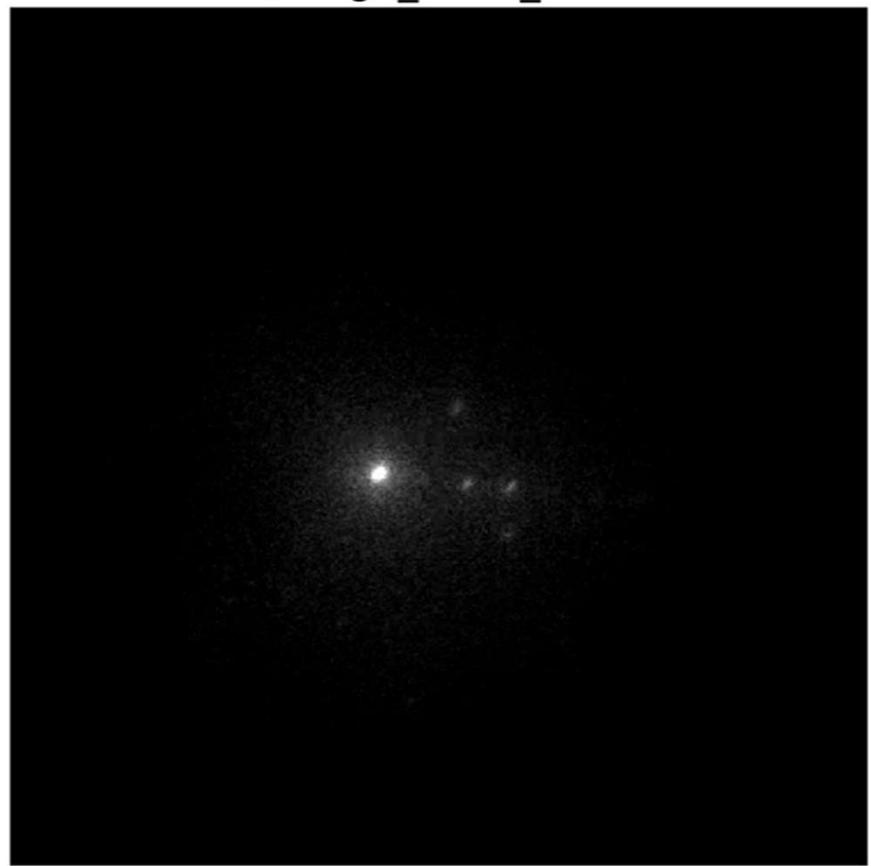


## Data collection (Zeolite Y)

images\image\_0000.h5

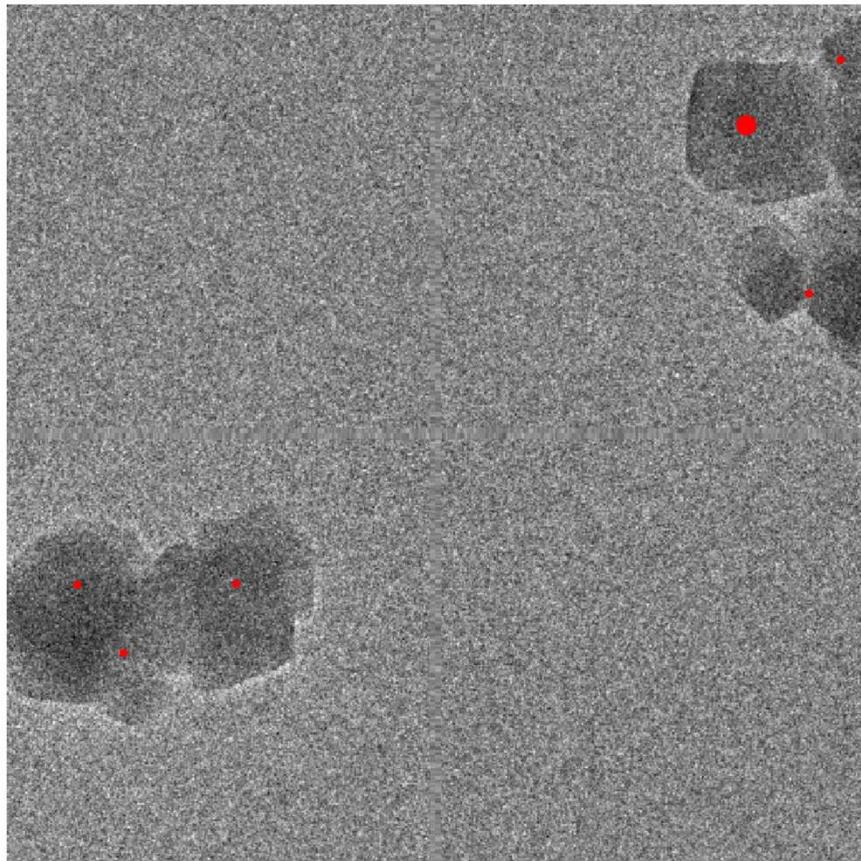


data\image\_0000\_0000.h5

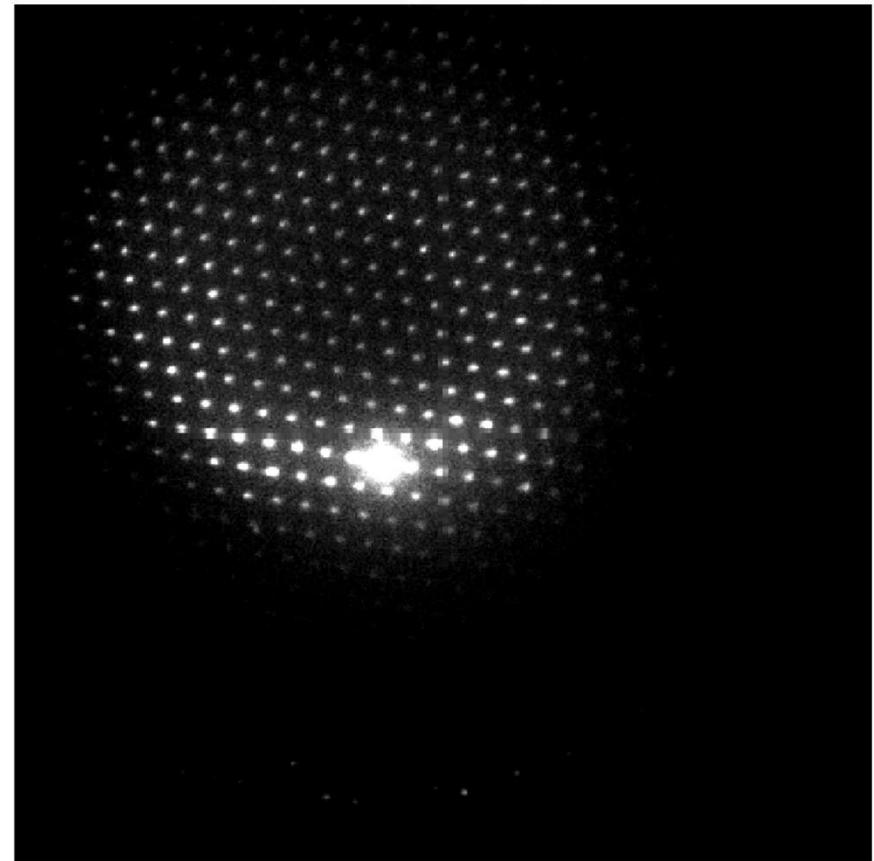


## Data collection 1/4

images\image\_0255.h5

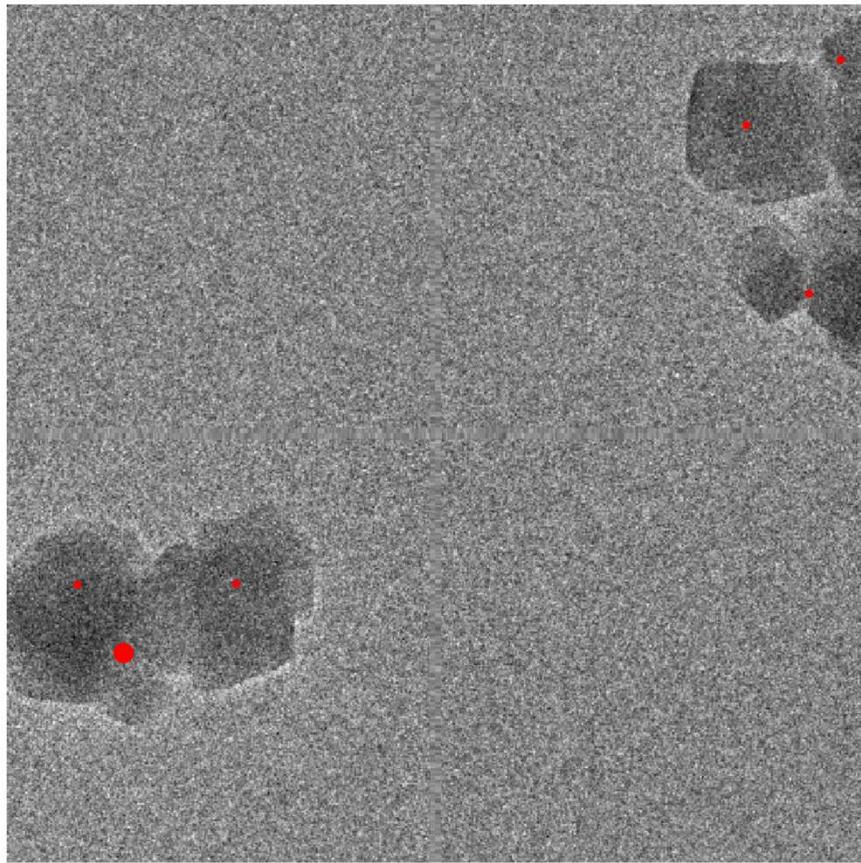


data\image\_0255\_0001.h5

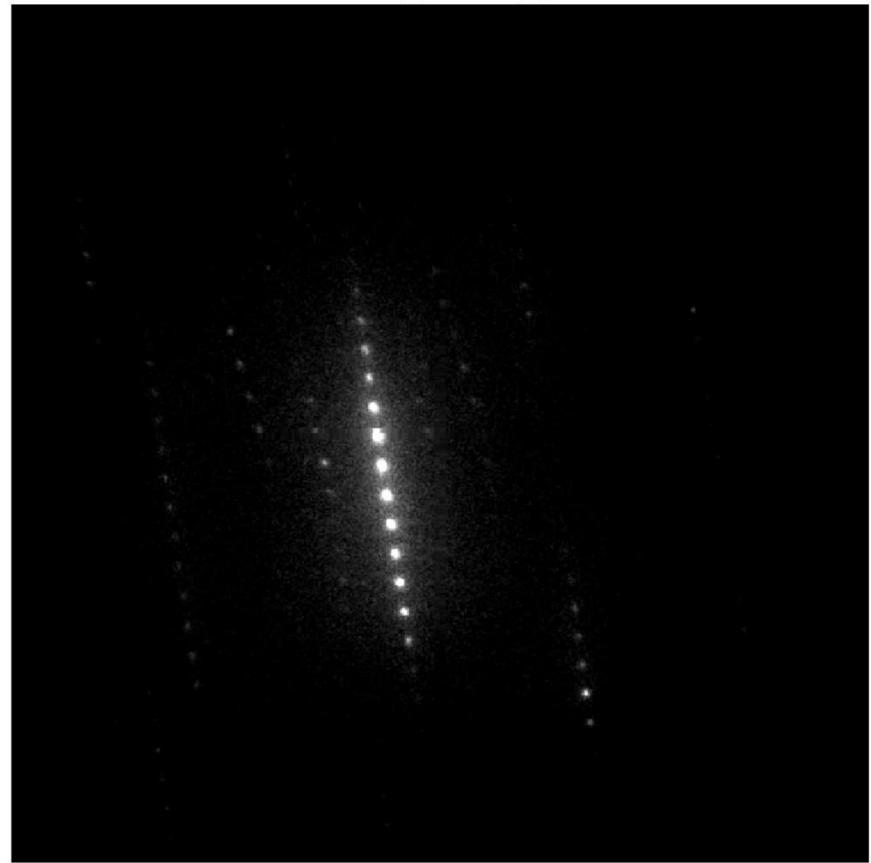


## Data collection 2/4

images\image\_0255.h5

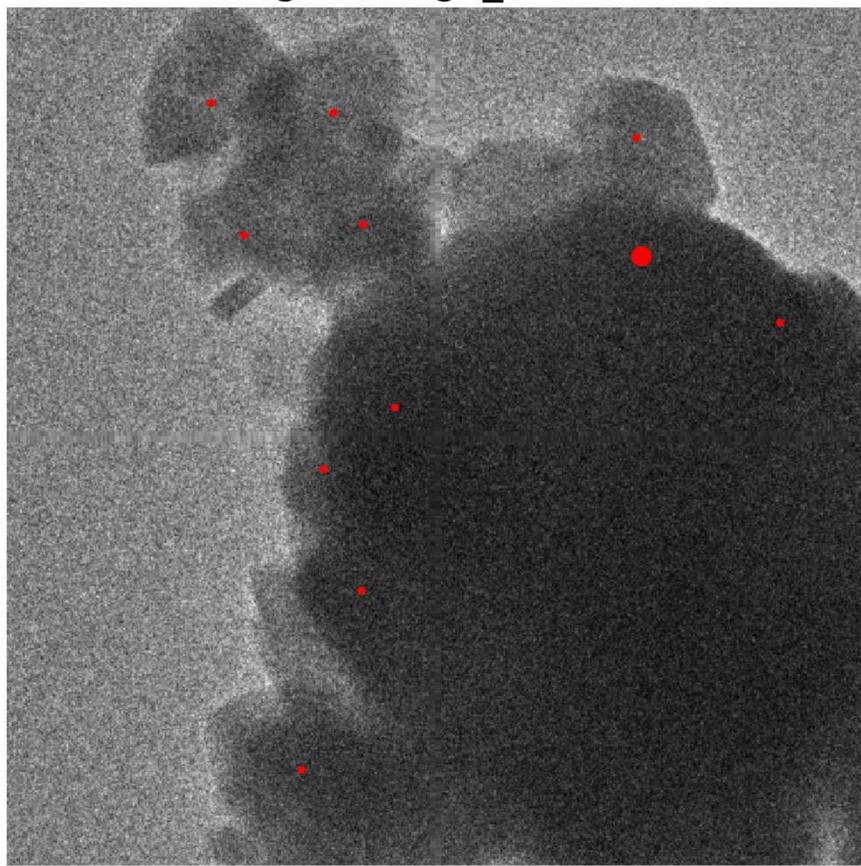


data\image\_0255\_0005.h5

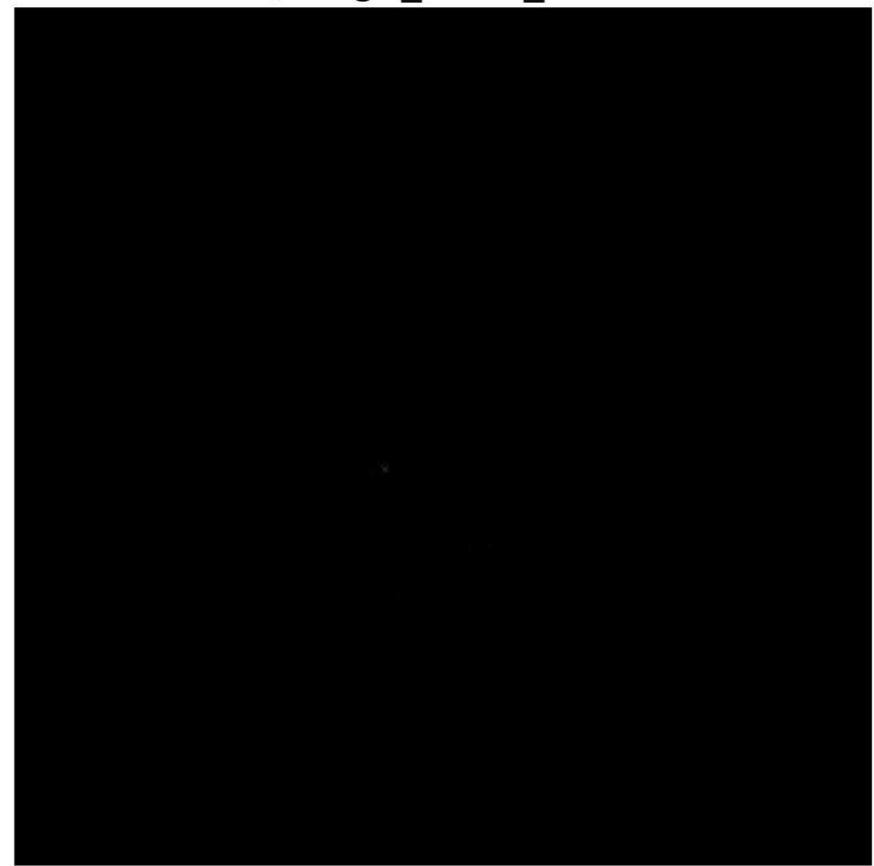


## Data collection 3/4

images\image\_0333.h5

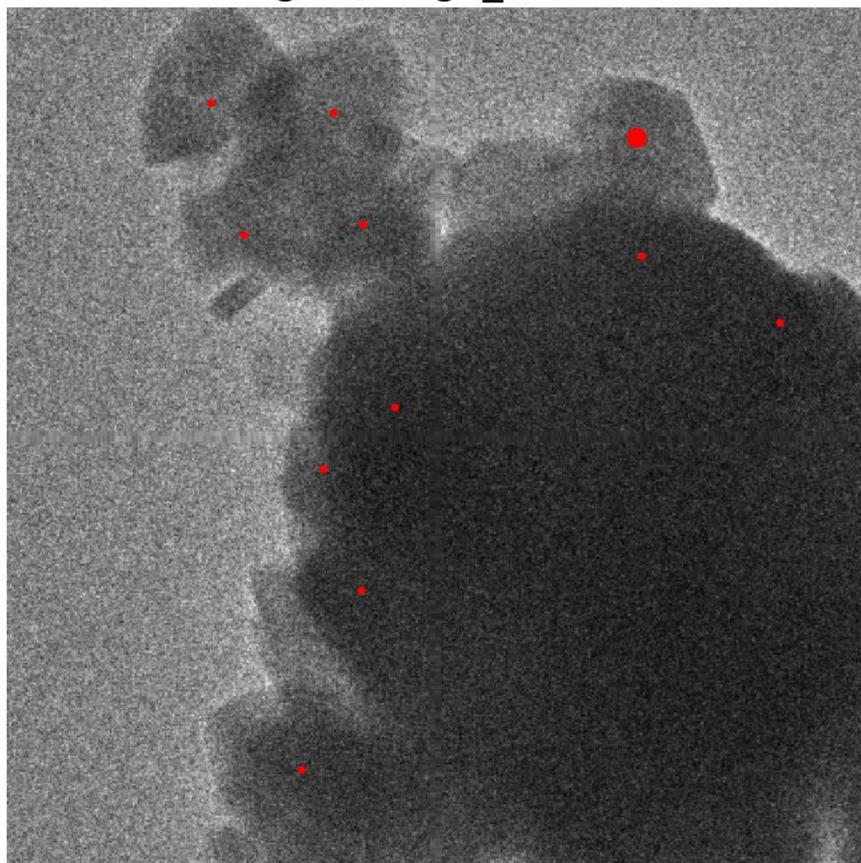


data\image\_0333\_0006.h5

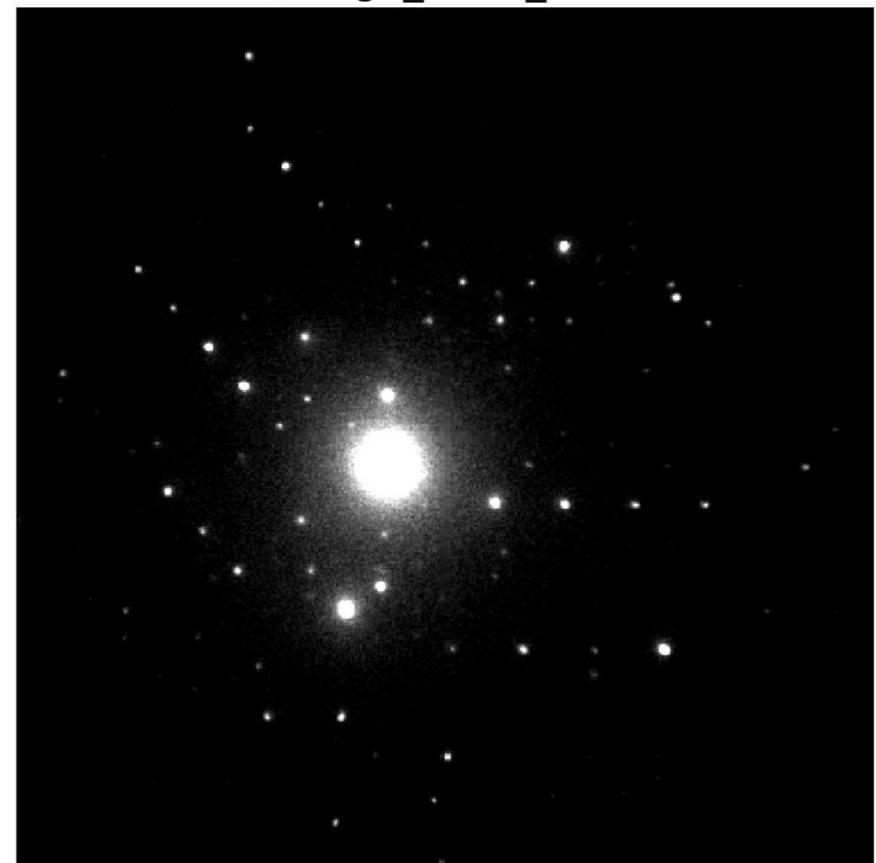


## Data collection 4/4

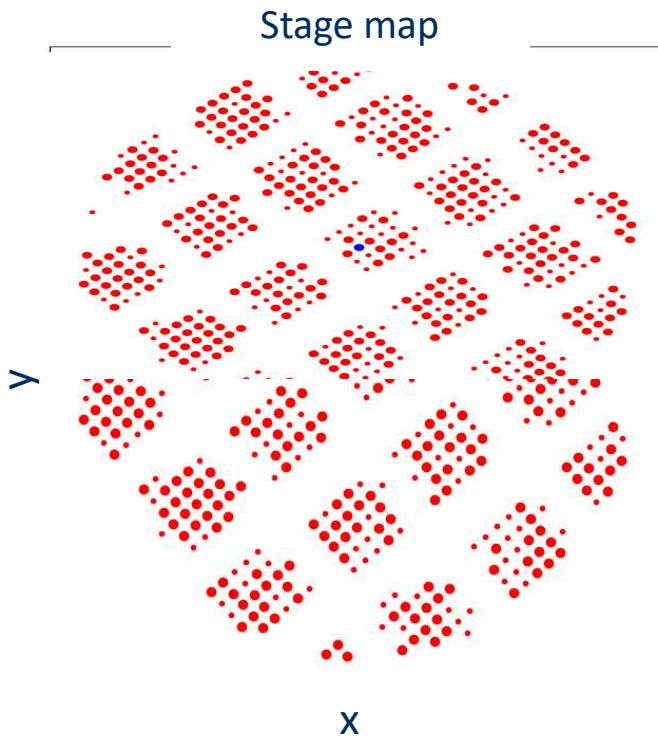
images\image\_0333.h5



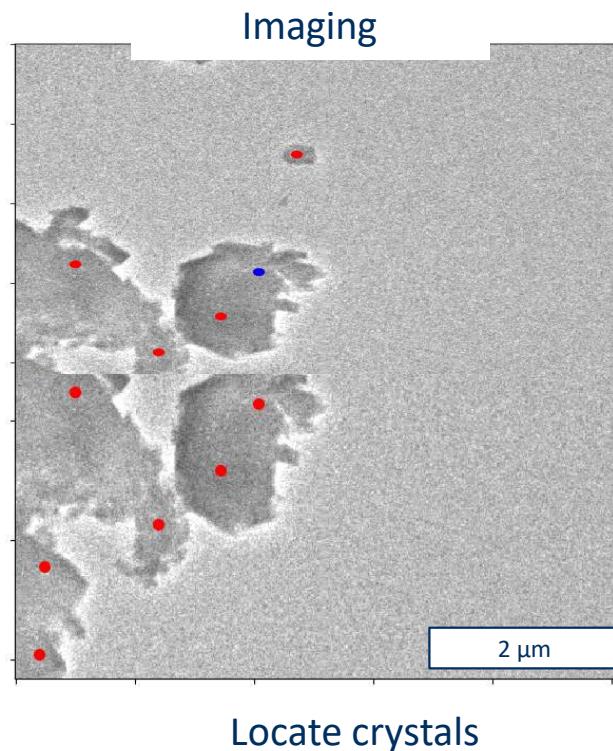
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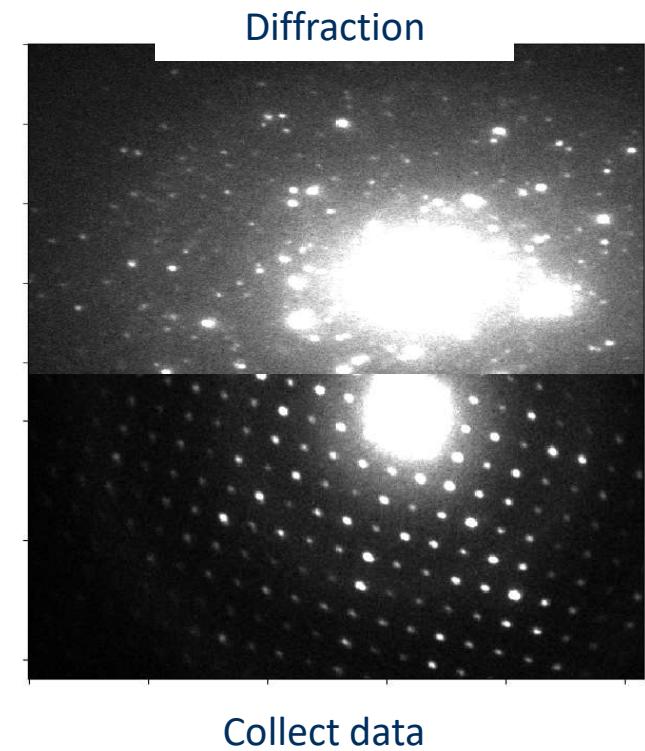
## Data collection (zeolite A)



200 x 200  $\mu\text{m}$   
484 images  
35 minutes

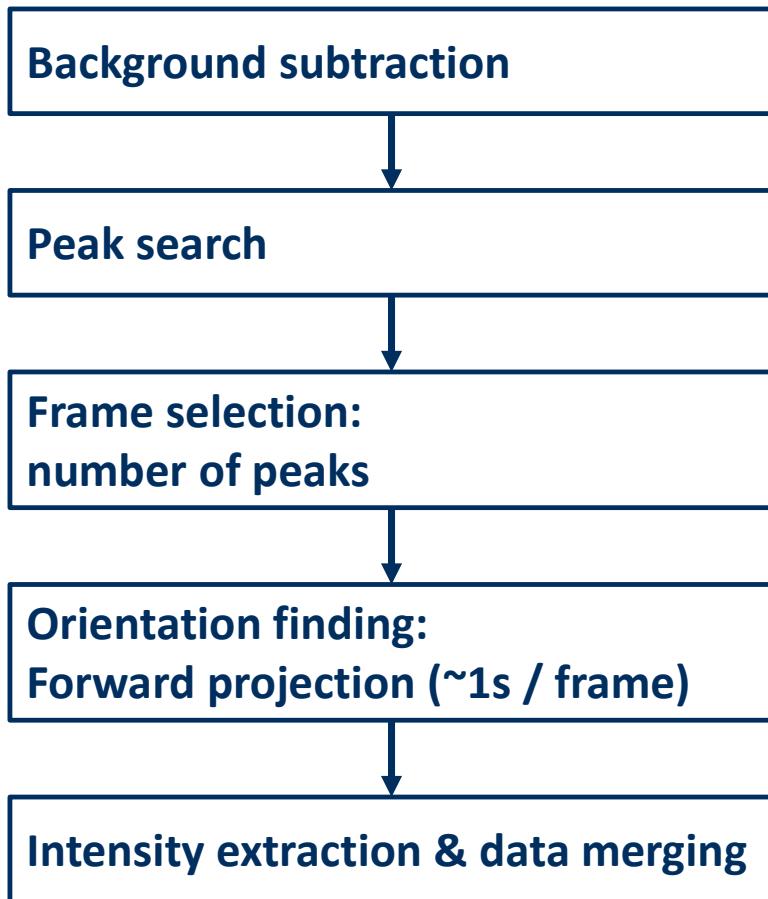


Probe size  $\sim$ 500 nm

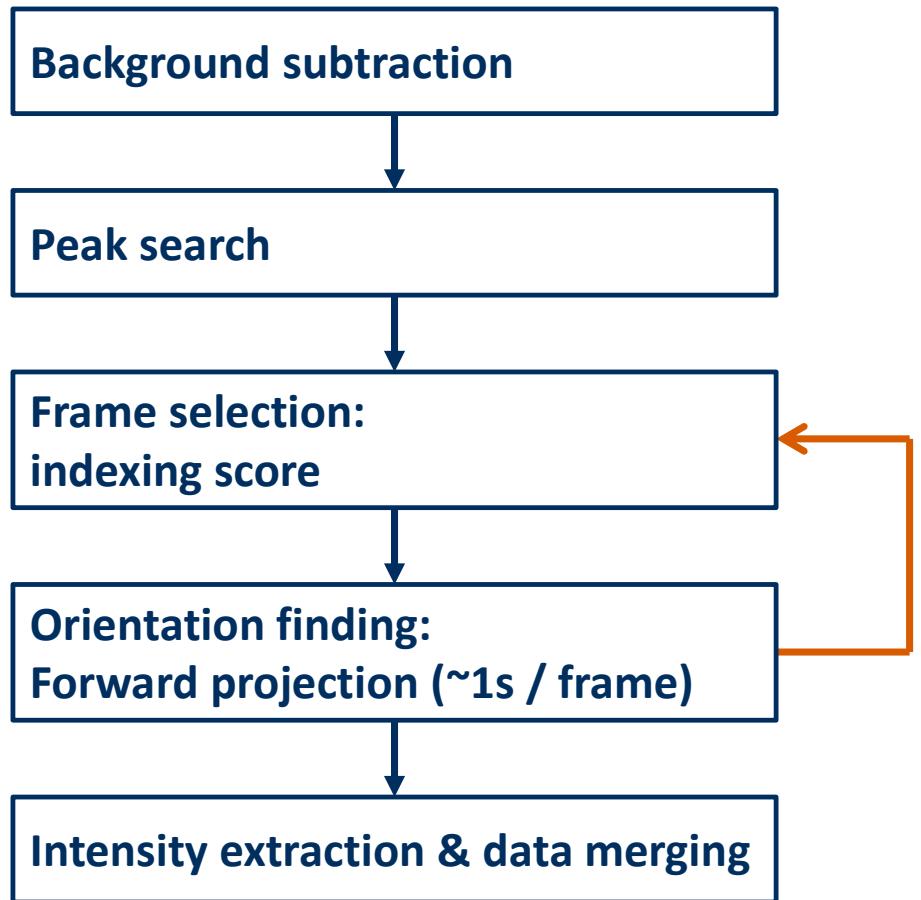


Total: 1107 patterns

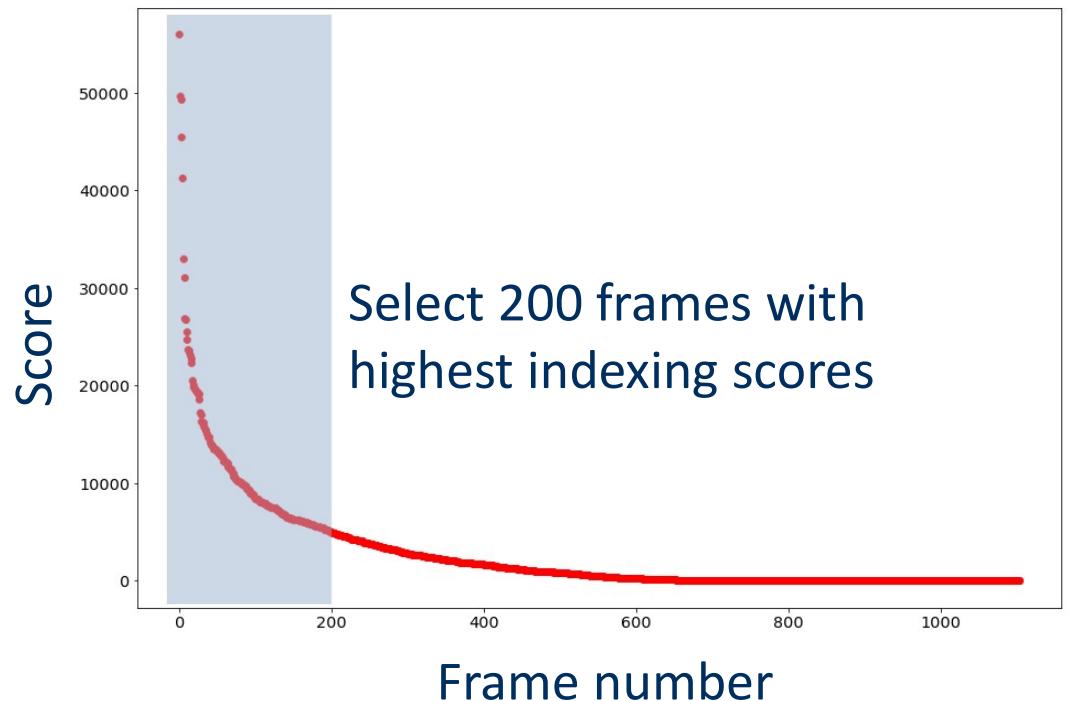
# Data processing



# Data processing



Zeolite A



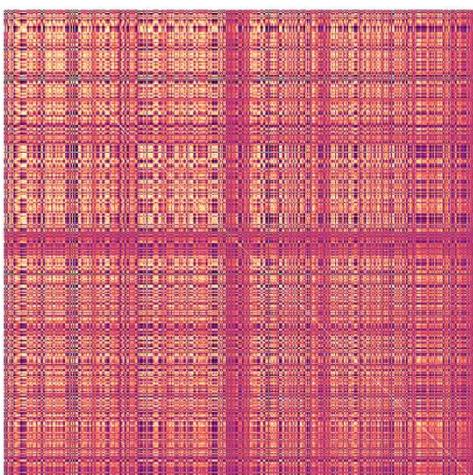
# Data Merging

## Challenges

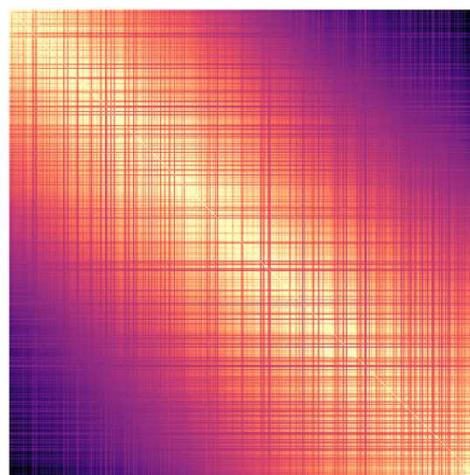
- Scaling
- Dynamical effects
- Reflection partiality

## *SerialMerge – rank-based merging*

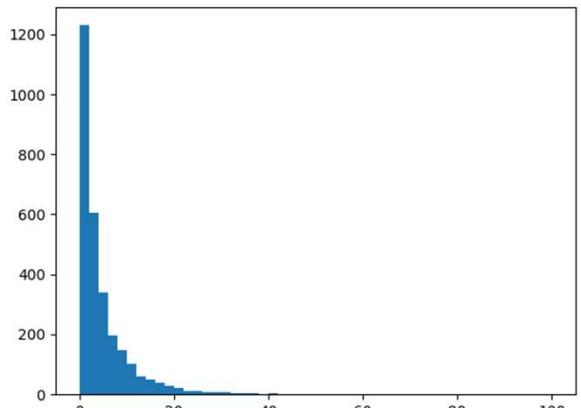
- Avoid scaling
- Avoid modelling intensities
- Robust with low quality data



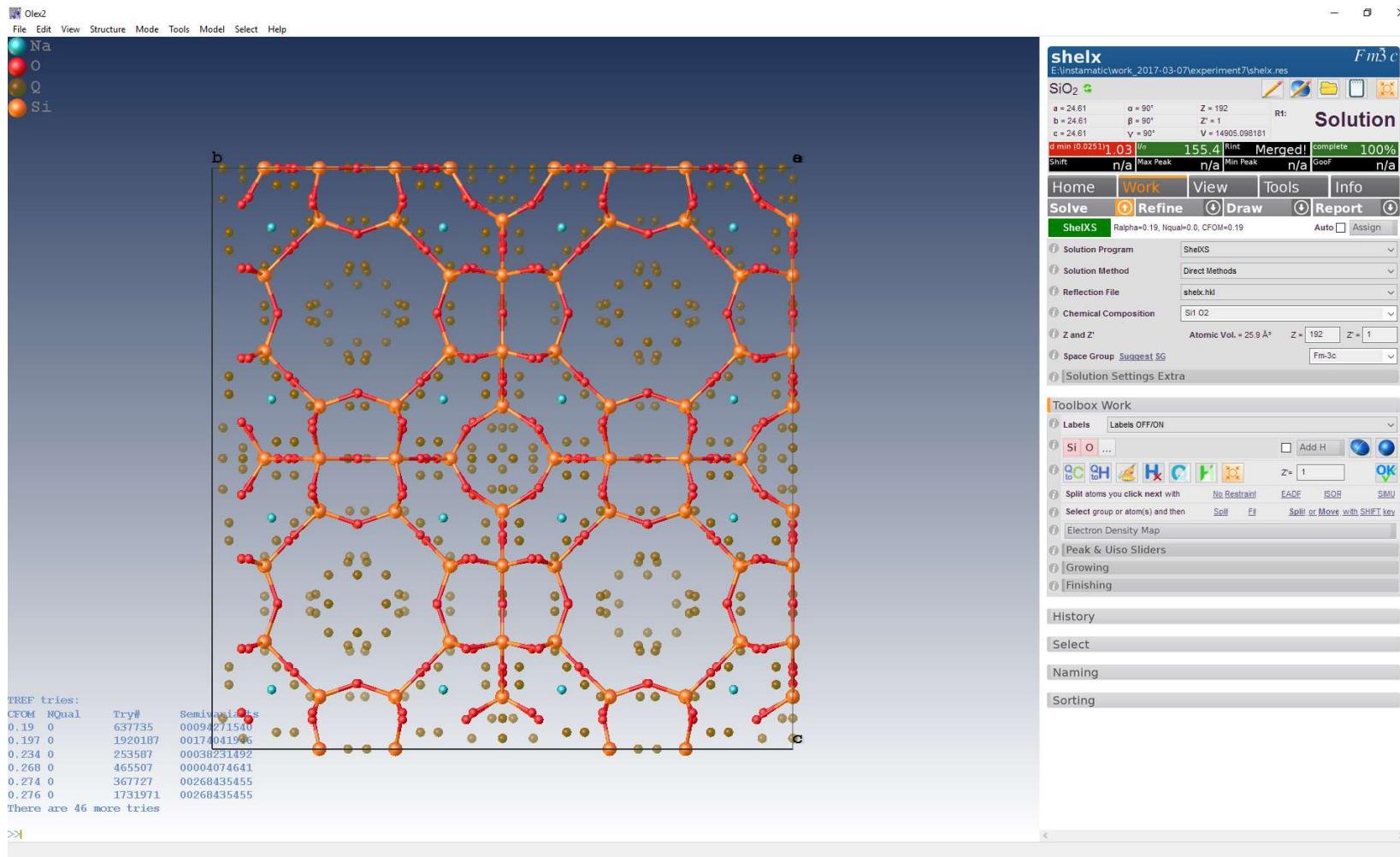
Retrieve  
ranking



Apply  
 $|F|$  histogram



# Structure determination

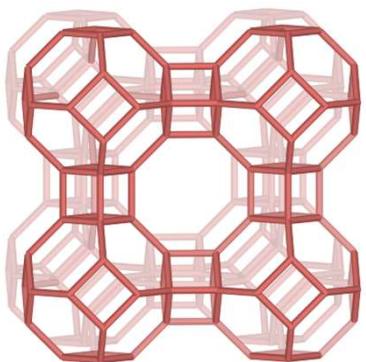


**Zeolite A**  
*Fm $\bar{3}$ c*  
 $a = 24.61 \text{ \AA}$   
 $\text{Si}_{96}\text{Al}_{96}\text{O}_{384}$   
 $Z = 192$

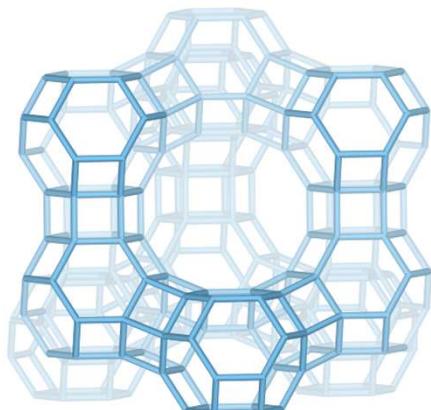
200 frames

**Reflections**  
Total: 19804  
Unique: 227  
 $d_{\min}$ : 1.03 Å  
Compl.: 100%

# Structures solved

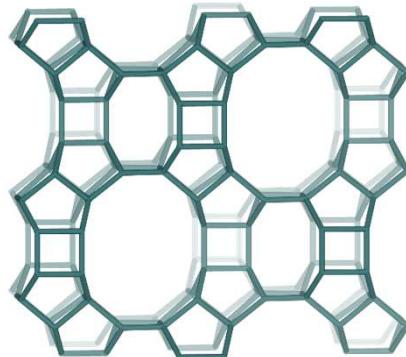


Zeolite A  
 $Fm\bar{3}c$   
 $a = 24.61 \text{ \AA}$   
 $\text{Si}_{96}\text{Al}_{96}\text{O}_{384}$   
 $Z = 192$

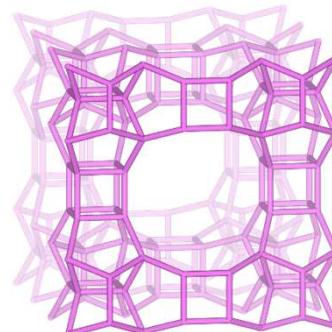


Zeolite Y  
 $Fd\bar{3}m$   
 $a = 24.74 \text{ \AA}$   
 $\text{Si}_{192}\text{O}_{384}$   
 $Z = 192$

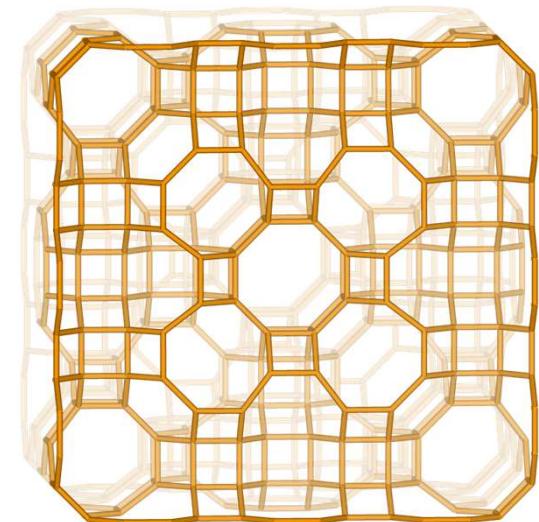
Direct methods  
ShelXS



Mordenite  
 $Cmcm$   
 $a = 18.11 \text{ \AA}$   
 $b = 20.53 \text{ \AA}$   
 $c = 7.53 \text{ \AA}$   
 $\text{Si}_{40}\text{Al}_8\text{O}_{96}$   
 $Z = 16$



Ge-BEC  
 $P4_2/mmc$   
 $a = 12.82 \text{ \AA}$   
 $c = 13.35 \text{ \AA}$   
 $\text{Si}/\text{Ge}_{32}\text{O}_{64}$   
 $Z = 16$



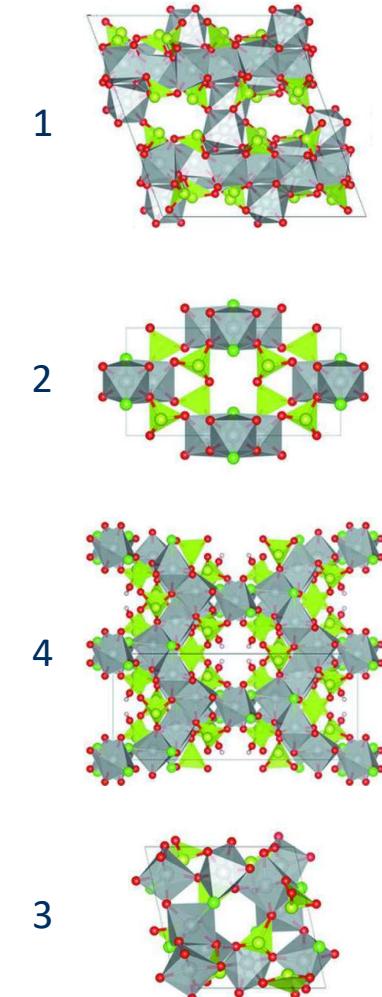
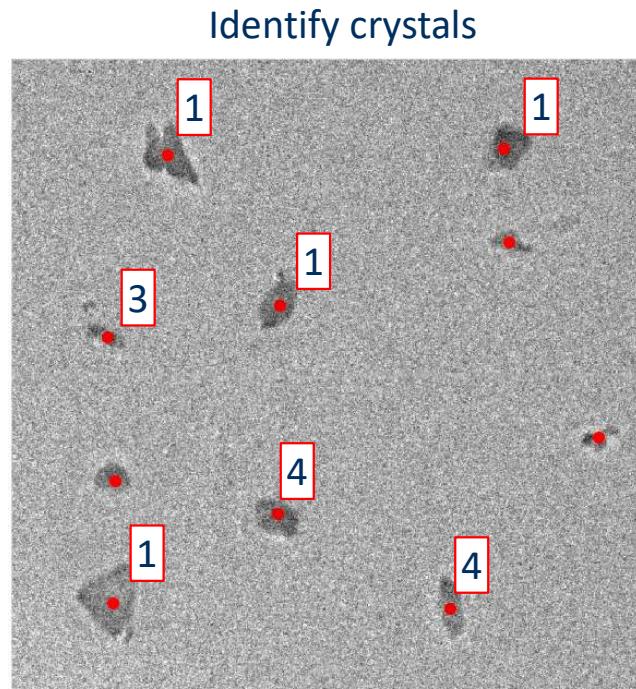
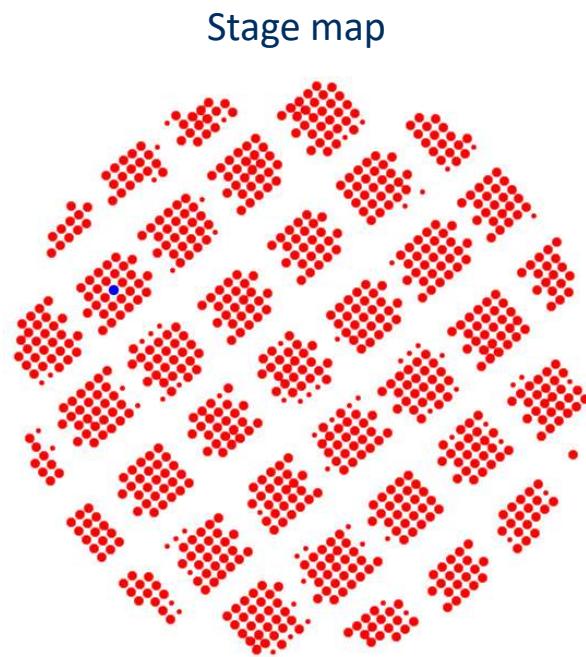
Paulingite  
 $Im\bar{3}m$   
 $a = 35.08 \text{ \AA}$   
 $\text{Si}_{672}\text{O}_{1344}$   
 $Z = 96$

Dual-space methods  
FOCUS

## Structures solved

	Time (min)	Patterns total	Patterns merged	Refs. total	Refs. unique	Compl. (%)	$d_{\min}$ (Å)	Method
<b>Zeolite A</b>	35	1107	200	19804	227	100	1.0	ShelXS
<b>Zeolite Y</b>	80	2506	99	7569	387	100	1.0	ShelXS
<b>Mordenite</b>	25	694	62	2882	603	(72)	1.0	FOCUS
<b>Ge-BEC</b>	100	6520	232	26144	481	(71)	1.0	FOCUS
<b>Paulingite</b>	40	780	83	9247	813	87	1.35	FOCUS

# Phase analysis (Ni-Se-O-Cl)



## Conclusions

- Serial ED data can be collected routinely & automatically
- SerialMerge algorithm can effectively merge serial ED data
- 100-200 diffraction patterns are enough for structure determination

## *Applications*

- Structure determination (of beam-sensitive materials)
- Crystal identification
  - Screening
  - Quantitative phase analysis
  - Polymorphism